

TOSHIBA Field Effect Transistor Silicon N Channel MOS Type (U-MOS II)

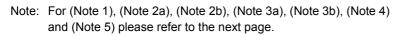
TPCS8203

Lithium Ion Battery Applications Portable Equipment Applications Notebook PCs

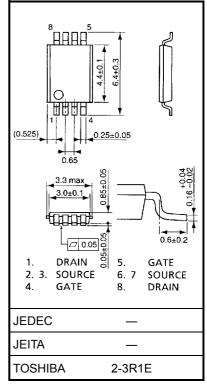
- Small footprint due to small and thin package
- Low drain-source ON resistance: R_{DS} (ON) = 17 m Ω (typ.)
- High forward transfer admittance: $|Y_{fs}| = 13 \text{ S} (typ.)$
- Low leakage current: $I_{DSS} = 10 \ \mu A \ (max) \ (V_{DS} = 20 \ V)$
- Enhancement-mode: $V_{th} = 0.5 \sim 1.2 \text{ V} (V_{DS} = 10 \text{ V}, \text{ ID} = 200 \text{ }\mu\text{A})$

Maximum Ratings (Ta = 25°C)

Char	acteristics	Symbol	Rating	Unit	
Drain-source vol	tage	V _{DSS}	20	V	
Drain-gate voltag	ge (R _{GS} = 20kΩ)	V _{DGR}	20	V	
Gate-source volt	age	V _{GSS}	±12	V	
Davia	D C (Note 1)	I _D	6	А	
Diament	Image: Source voltageV V DSS20source voltage(RGS = 20k Ω)V DGR20source voltageV VGSS±12currenD C(Note 1)IDPulse(Note 1)IDP24power tition s) (Note 2a)Single-device operation (Note 3b)PD (1)1.1Single-device value at dual operation (Note 3b)PD (2)0.75power tition s) (Note 2b)Single-device value at dual operation (Note 3b)PD (2)0.75single-device value at dual operation (Note 3b)PD (2)0.350.35pulse avalanche energy (Note 4)EAS234234tive avalanche energy -device value at operationEAR0.11	A			
Drain power dissipation	operation	P _{D (1)}	1.1	W	
(t = 10s) (Note 2a)	at dual operation	P _{D(2)}	0.75		
Drain power dissipation (t = 10s) (Note 2b)	operation	P _{D (1)}	0.6	W	
	at dual operation	P _{D (2)}	0.35		
Single pulse ava		E _{AS}	234	mJ	
Avalanche currei	nt	I _{AR}	6	А	
Single-device va		E _{AR}	0.11	mJ	
Channel tempera	ature	T _{ch}	150	°C	
Storage tempera	ture range	T _{stg}	-55~150	°C	

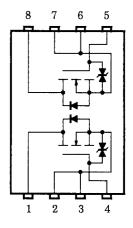


This transistor is an electrostatic sensitive device. Please handle with caution.



Weight: 0.035 g (typ.)

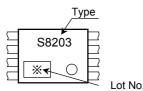
Circuit Configuration



Thermal Characteristics

Characteristics	Symbol	Max	Unit		
Thermal resistance, channel to ambient	Single-device operation (Note 3a)	R _{th (ch-a) (1)}	114		
(t = 10s) (Note 2a)	Single-device value at dual operation (Note 3b)	R _{th (ch-a) (2)}	167	°C/W	
Thermal resistance, channel to ambient	Single-device operation (Note 3a)	R _{th (ch-a) (1)}	208	C/VV	
(t = 10s) (Note 2b)	Single-device value at dual operation (Note 3b)	R _{th (ch-a) (2)}	357		

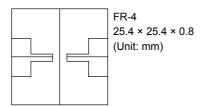
Marking (Note 6)

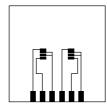


Note 1: Please use devices on condition that the channel temperature is below 150°C.

Note 2:

- a) Device mounted on a glass-epoxy board (a)
- b) Device mounted on a glass-epoxy board (b)





FR-4 25.4 × 25.4 × 0.8 (Unit: mm)

Note 3:

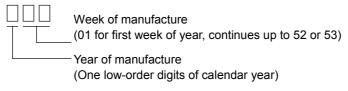
- a) The power dissipation and thermal resistance values are shown for a single device (During single-device operation, power is only applied to one device.).
- b) The power dissipation and thermal resistance values are shown for a single device (During dual operation, power is evenly applied to both devices.).

Note 4: V_{DD} = 16 V, T_{ch} = 25°C (Initiaal), L = 5.0 mH, R_G = 25 Ω , I_{AR} = 6.0 A

Note 5: Repetitive rating; pulse width limited by max channel temperature.

Note 6: ● on lower right of the marking indicates Pin 1.

※ Weekly code: (Three digits)



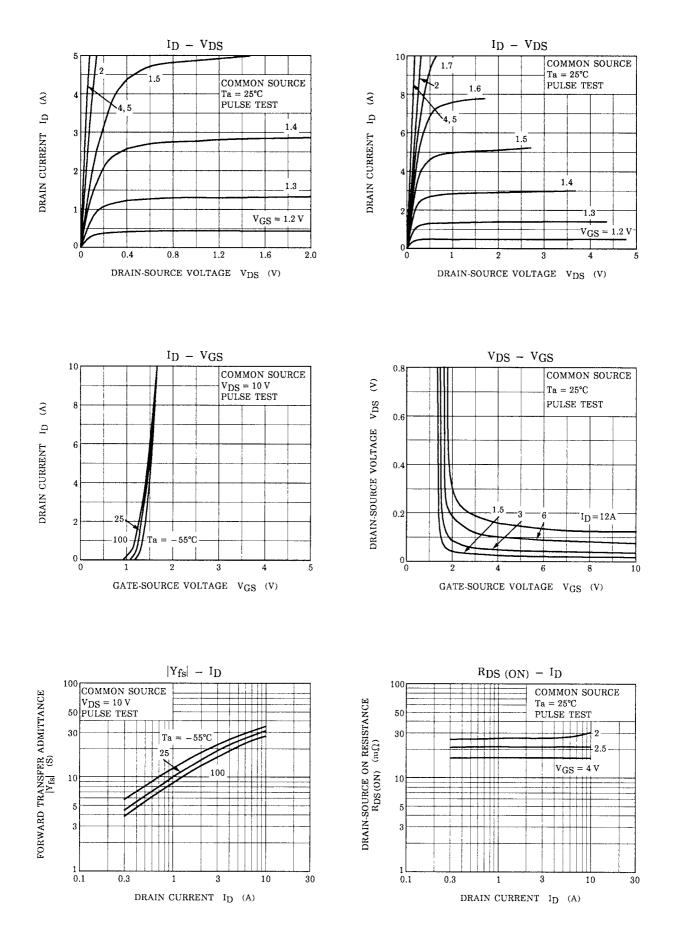
Electrical Characteristics (Ta = 25°C)

Characteristics		Symbol	Test Condition	Min	Тур.	Max	Unit
Gate leakage cur	rent	I _{GSS}	V _{GS} = ±10 V, V _{DS} = 0 V	_	— — ±10		μA
Drain cut-OFF cu	ırrent	I _{DSS}	V _{DS} = 20 V, V _{GS} = 0 V	_	_	10	μA
Drain-source bre	akdown voltage	V (BR) DSS	I _D = 10 mA, V _{GS} = 0 V	20	_	_	v
Diam-source bre	ardown voltage	V (BR) DSX	I_D = 10 mA, V_{GS} = -12 V	8 — —		v	
Gate threshold ve	oltage	V _{th}	V _{DS} = 10 V, I _D = 200 μA	0.5	_	1.2	V
		R _{DS (ON)}	V _{GS} = 2.0 V, I _D = 4.2 A	_	27	45	
Drain-source ON resistance Forward transfer admittance		R _{DS (ON)}	V _{GS} = 2.5 V, I _D = 4.2 A	_	22	29	mΩ
		R _{DS (ON)}	V _{GS} = 4 V, I _D = 4.8 A	_	17	24	
Forward transfer admittance		Y _{fs}	V _{DS} = 10 V, I _D = 3 A	6.5	13		S
Input capacitance		C _{iss}	V _{DS} = 10 V, V _{GS} = 0 V, f = 1 MHz	_	1160		pF
Reverse transfer capacitance		C _{rss}		_	190		pF
· ·		C _{oss}		_	270	_	pF
	Rise time	tr	$V_{GS} \xrightarrow{5 V}_{0 V} \xrightarrow{I_D = 3 A}_{V_{OUT}}$ $V_{OUT} \xrightarrow{V_{OUT}}_{R_L = 3.3 \Omega}$ $V_{DD} = 10 V$ $Duty \le 1\%, t_w = 10 \mu s$	_	6.9	_	
Gate threshold voltage Drain-source ON resis Forward transfer admit Input capacitance Reverse transfer capa Output capacitance Riverse transfer capa Tu Switching time Fa Tu Total gate charge (gate-source plus gate	Turn-ON time	t _{on}		_	13	_	
	Fall time	t _f		_	18	_	ns
	Turn-OFF time	t _{off}		_	62		
Total gate charge (gate-source plus gate-drain)		Qg	V _{DD} ≈ 16 V, V _{GS} = 5 V, I _D = 6 A		18		nC
Gate-source charge		Q _{gs}			12	_	nC
Gate-drain ("mille	er") charge	Q _{gd}			6		nC

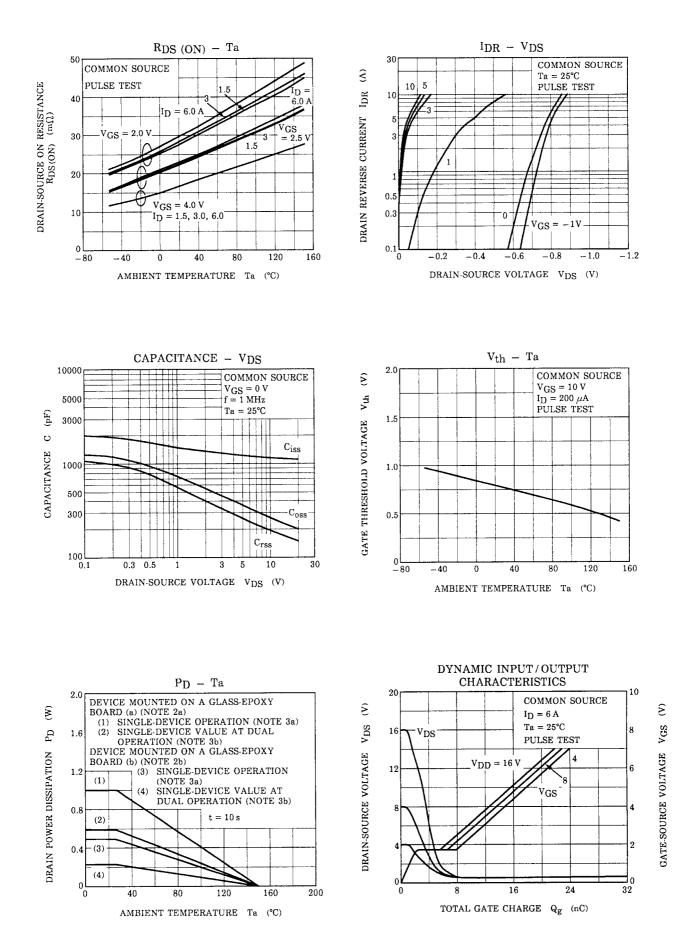
Source-Drain Ratings and Characteristics (Ta = 25°C)

Charact	eristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Drain reverse current	Pulse (Note 1)	I _{DRP}	—	_	_	24	А
Forward voltage	(diode)	V _{DSF} I _{DR} = 6 A, V _{GS} = 0 V — 2 2 2 <th2< th=""> 2 2 <th2<< td=""><td>-1.2</td><td>V</td></th2<<></th2<>		-1.2	V		

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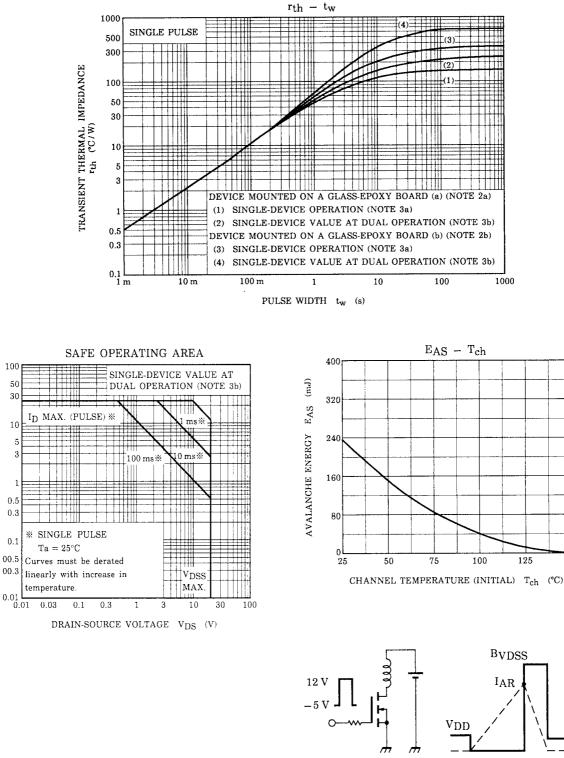
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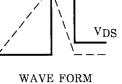
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DRAIN CURRENT ID



TEST CIRCUIT



150

 $T_{ch} = 25^{\circ}C$ (Initial) BVDSS $P_{ch} = 25 \text{ C} (IIIIIII)$ $P_{eak} I_{AR} = 6 \text{ A}, R_G = 25 \Omega \quad E_{AS} = \frac{1}{2} \cdot L \cdot I^2 \cdot (\frac{BVDSS}{BVDSS} - VDD)$ $V_{DD} = 16 V, L = 5.0 mH$

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